

**3.0 V OPERATION SILICON RF POWER LD-MOS FET  
FOR 460 MHz 0.6 W TRANSMISSION AMPLIFIERS****DESCRIPTION**

The NE552R679A is an N-channel silicon power laterally diffused MOS FET specially designed as the transmission power amplifier for 3.0 V FRS (Family Radio Service). Dies are manufactured using our NEWMOS2 technology (our WSi gate lateral-diffusion MOS FET) and housed in a surface mount package. This device can deliver 28.0 dBm output power with 60% power added efficiency at 460 MHz under the 3.0 V supply voltage.

**FEATURES**

- High output power :  $P_{out} = 28.0$  dBm TYP. ( $V_{DS} = 3.0$  V,  $I_{Dset} = 300$  mA,  $f = 460$  MHz,  $P_{in} = 15$  dBm)
- High power added efficiency :  $\eta_{add} = 60\%$  TYP. ( $V_{DS} = 3.0$  V,  $I_{Dset} = 300$  mA,  $f = 460$  MHz,  $P_{in} = 15$  dBm)
- High linear gain :  $G_L = 20$  dB TYP. ( $V_{DS} = 3.0$  V,  $I_{Dset} = 300$  mA,  $f = 460$  MHz,  $P_{in} = 5$  dBm)
- Surface mount package :  $5.7 \times 5.7 \times 1.1$  mm MAX.
- Single supply :  $V_{DS} = 2.8$  to  $6.0$  V

**APPLICATIONS**

- Family Radio Service : 3.0 V Handsets

**ORDERING INFORMATION**

Part Number	Package	Marking	Supplying Form
NE552R679A-T1	79A	AU	<ul style="list-style-type: none"> <li>• 12 mm wide embossed taping</li> <li>• Gate pin face the perforation side of the tape</li> <li>• Qty 1 kpcs/reel</li> </ul>
NE552R679A-T1A			<ul style="list-style-type: none"> <li>• 12 mm wide embossed taping</li> <li>• Gate pin face the perforation side of the tape</li> <li>• Qty 5 kpcs/reel</li> </ul>

**Remark** To order evaluation samples, contact your nearby sales office.

Part number for sample order: NE552R679A

**Caution** Observe precautions when handling because these devices are sensitive to electrostatic discharge.

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Not all devices/types available in every country. Please check with local NEC Compound Semiconductor Devices representative for availability and additional information.

**ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = +25°C)**

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Parameter	Symbol	Ratings	Unit
Drain to Source Voltage	V <sub>DS</sub>	15.0	V
Gate to Source Voltage	V <sub>GS</sub>	5.0	V
Drain Current	I <sub>DS</sub>	350	mA
Drain Current (Pulse Test)	I <sub>DS</sub> <sup>Note</sup>	600	mA
Total Power Dissipation	P <sub>tot</sub>	10	W
Channel Temperature	T <sub>ch</sub>	125	°C
Storage Temperature	T <sub>stg</sub>	–55 to +125	°C

**Note** Duty Cycle 50%, T<sub>on</sub> ≤ 1 s**RECOMMENDED OPERATING CONDITIONS**

Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Drain to Source Voltage	V <sub>DS</sub>		2.8	3.0	6.0	V
Gate to Source Voltage	V <sub>GS</sub>		0	2.0	3.0	V
Drain Current	I <sub>DS</sub>		–	300	500	mA
Input Power	P <sub>in</sub>	f = 460 MHz, V <sub>DS</sub> = 3.0 V	14	15	20	dBm

**ELECTRICAL CHARACTERISTICS****(T<sub>A</sub> = +25°C, Unless otherwise specified, using NEC standard test fixture)**

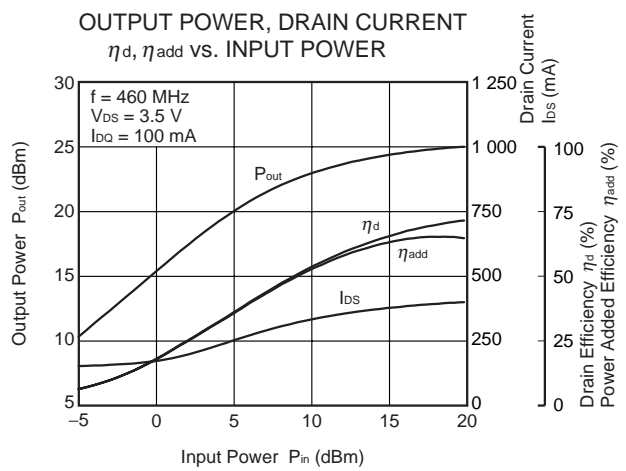
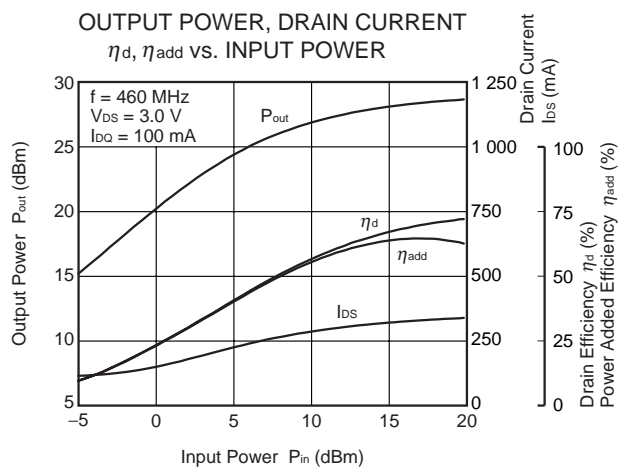
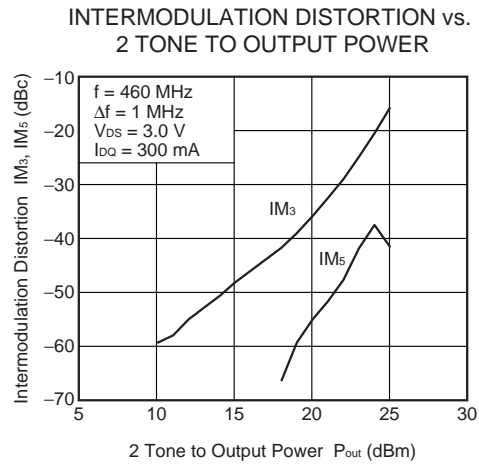
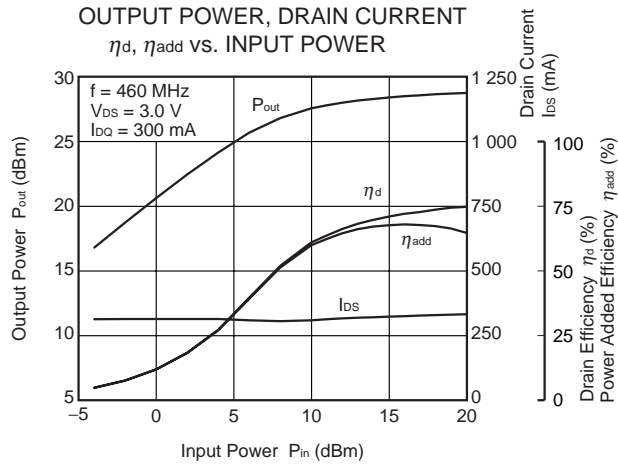
Parameter	Symbol	Test Conditions	MIN.	TYP.	MAX.	Unit
Gate to Source Leak Current	I <sub>GSS</sub>	V <sub>GS</sub> = 5.0 V	–	–	100	nA
Saturated Drain Current (Zero Gate Voltage Drain Current)	I <sub>DSS</sub>	V <sub>DS</sub> = 8.0 V	–	–	100	nA
Gate Threshold Voltage	V <sub>th</sub>	V <sub>DS</sub> = 3.5 V, I <sub>DS</sub> = 1 mA	1.0	1.4	1.9	V
Thermal Resistance	R <sub>th</sub>	Channel to Case	–	–	10	°C/W
Transconductance	g <sub>m</sub>	V <sub>DS</sub> = 3.0 V, I <sub>DS</sub> = 300 mA	–	0.6	–	S
Drain to Source Breakdown Voltage	BV <sub>DSS</sub>	I <sub>DSS</sub> = 10 μA	15	18	–	V
Output Power	P <sub>out</sub>	f = 460 MHz, V <sub>DS</sub> = 3.0 V, P <sub>in</sub> = 15 dBm, I <sub>Dset</sub> = 300 mA (RF OFF) , <b>Note1</b>	26.0	28.0	–	dBm
Drain Current	I <sub>DS</sub>		–	320	–	mA
Power Added Efficiency	η <sub>add</sub>		55	60	–	%
Linear Gain <sup>Note2</sup>	G <sub>L</sub>		–	20	–	dB

**Note 1.** DC performance is 100% testing. RF performance is testing several samples per wafer.

Wafer rejection criteria for standard devices is 1 reject for several samples.

**2.** P<sub>in</sub> = 5 dBm

TYPICAL CHARACTERISTICS ( $T_A = +25^\circ\text{C}$ )



**Remark** The graphs indicate nominal characteristics.

## S-PARAMETERS

Test Conditions:  $V_{DS} = 3.0\text{ V}$ ,  $I_{Dset} = 300\text{ mA}$ ,  $T_A = +25^\circ\text{C}$ 

Frequency GHz	S11			S21			S12		S22		MAG <sup>Note</sup> dB	MSG <sup>Note</sup> dB	K –
	Mag.	Ang.	dB	Mag.	Ang.	dB	Mag.	Ang.	Mag.	Ang.			
0.1	0.655	–120.2	21.2	11.42	115.3	–31.6	0.026	28.7	0.633	–167.5		26.4	0.59
0.2	0.651	–142.0	17.2	7.25	99.3	–29.0	0.035	10.3	0.757	–167.9		23.1	0.36
0.3	0.666	–156.1	13.8	4.89	88.2	–29.3	0.034	–0.1	0.796	–173.0		21.5	0.40
0.4	0.660	–161.4	11.5	3.74	81.6	–29.2	0.034	–5.6	0.808	–175.0		20.4	0.50
0.5	0.656	–165.8	9.4	2.96	77.2	–29.2	0.035	–11.8	0.815	–175.9		19.3	0.62
0.6	0.655	–168.4	7.8	2.46	72.6	–29.3	0.034	–15.9	0.819	–176.8		18.6	0.76
0.7	0.654	–170.2	6.5	2.10	68.4	–29.5	0.033	–20.1	0.823	–177.4		18.0	0.91
0.8	0.658	–171.8	5.2	1.81	64.4	–29.6	0.033	–24.2	0.828	–178.0	16.2		1.04
0.9	0.656	–172.8	4.1	1.61	60.6	–29.7	0.033	–27.6	0.831	–179.4	14.2		1.20
1.0	0.658	–173.8	3.1	1.43	56.6	–29.8	0.032	–31.5	0.835	–179.9	12.8		1.37
1.1	0.663	–175.0	2.1	1.27	53.3	–30.0	0.031	–35.3	0.840	179.6	11.7		1.54
1.2	0.668	–175.8	1.1	1.14	49.9	–30.2	0.031	–39.1	0.843	179.2	10.7		1.75
1.3	0.668	–176.8	0.4	1.04	46.6	–30.3	0.030	–42.1	0.846	178.7	9.8		1.93
1.4	0.668	–177.6	–0.4	0.96	43.7	–30.6	0.030	–45.4	0.851	178.2	9.1		2.14
1.5	0.672	–178.5	–1.1	0.88	40.6	–30.7	0.029	–49.0	0.853	177.7	8.2		2.38
1.6	0.674	–179.2	–1.8	0.81	37.5	–31.0	0.028	–51.8	0.857	177.4	7.6		2.61
1.7	0.673	–180.0	–2.5	0.75	34.6	–31.1	0.028	–55.3	0.859	176.6	6.8		2.87
1.8	0.675	179.2	–3.2	0.69	31.7	–31.3	0.027	–58.6	0.862	176.1	6.1		3.20
1.9	0.677	178.5	–3.8	0.65	28.9	–31.6	0.026	–61.5	0.864	175.5	5.5		3.51
2.0	0.677	177.8	–4.4	0.61	26.4	–31.7	0.026	–64.6	0.867	174.9	5.0		3.76
2.1	0.677	177.0	–4.9	0.57	24.0	–31.9	0.025	–68.3	0.869	174.2	4.4		4.12
2.2	0.677	176.2	–5.4	0.54	21.2	–32.2	0.025	–71.4	0.869	173.6	3.8		4.57
2.3	0.681	175.4	–6.0	0.50	19.2	–32.2	0.025	–75.1	0.863	172.6	3.0		5.14
2.4	0.677	174.7	–6.5	0.48	16.6	–32.5	0.024	–78.2	0.873	172.4	2.8		5.35
2.5	0.675	174.6	–6.9	0.45	13.9	–32.7	0.023	–82.0	0.874	171.7	2.2		5.82
2.6	0.674	173.8	–7.4	0.43	11.7	–32.8	0.023	–85.1	0.874	170.9	1.7		6.29
2.7	0.673	173.2	–7.9	0.40	9.5	–33.0	0.022	–89.7	0.873	170.1	1.2		6.90
2.8	0.670	172.3	–8.3	0.39	7.8	–33.2	0.022	–92.3	0.875	169.4	0.8		7.45
2.9	0.667	171.4	–8.7	0.37	5.7	–33.4	0.021	–96.7	0.874	168.7	0.3		8.10
3.0	0.665	170.7	–9.1	0.35	3.5	–33.4	0.021	–101.5	0.873	167.9	–0.2		8.64
3.1	0.662	169.9	–9.5	0.33	1.4	–33.7	0.021	–106.4	0.873	167.2	–0.8		9.63
3.2	0.648	168.9	–9.8	0.32	–0.1	–34.1	0.020	–111.8	0.879	166.8	–1.0		10.28
3.3	0.656	168.6	–10.4	0.30	–1.4	–34.6	0.019	–117.6	0.872	165.7	–1.7		12.13
3.4	0.652	167.6	–10.6	0.29	–2.8	–35.3	0.017	–122.0	0.871	164.9	–2.1		13.80
3.5	0.651	167.1	–11.0	0.28	–4.5	–35.6	0.017	–123.8	0.871	164.1	–2.4		14.87
3.6	0.648	166.2	–11.3	0.27	–6.6	–35.6	0.017	–126.7	0.870	163.1	–2.8		15.51
3.7	0.644	165.4	–11.6	0.26	–7.9	–35.7	0.016	–130.5	0.869	162.3	–3.2		16.66
3.8	0.641	164.7	–12.0	0.25	–10.1	–36.0	0.016	–135.9	0.868	161.4	–3.7		18.41
3.9	0.636	163.8	–12.3	0.24	–11.5	–36.1	0.016	–140.3	0.867	160.4	–4.0		19.61
4.0	0.633	163.0	–12.6	0.23	–12.5	–36.2	0.015	–144.7	0.865	159.4	–4.4		21.02

**Note** When  $K \geq 1$ , the MAG (Maximum Available Gain) is used. 
$$\text{MAG} = \left| \frac{S_{21}}{S_{12}} \right| (K - \sqrt{K^2 - 1})$$

When  $K < 1$ , the MSG (Maximum Stable Gain) is used. 
$$\text{MSG} = \left| \frac{S_{21}}{S_{12}} \right|, K = \frac{1 + |\Delta|^2 - |S_{11}|^2 - |S_{22}|^2}{2 \cdot |S_{12}| \cdot |S_{21}|},$$

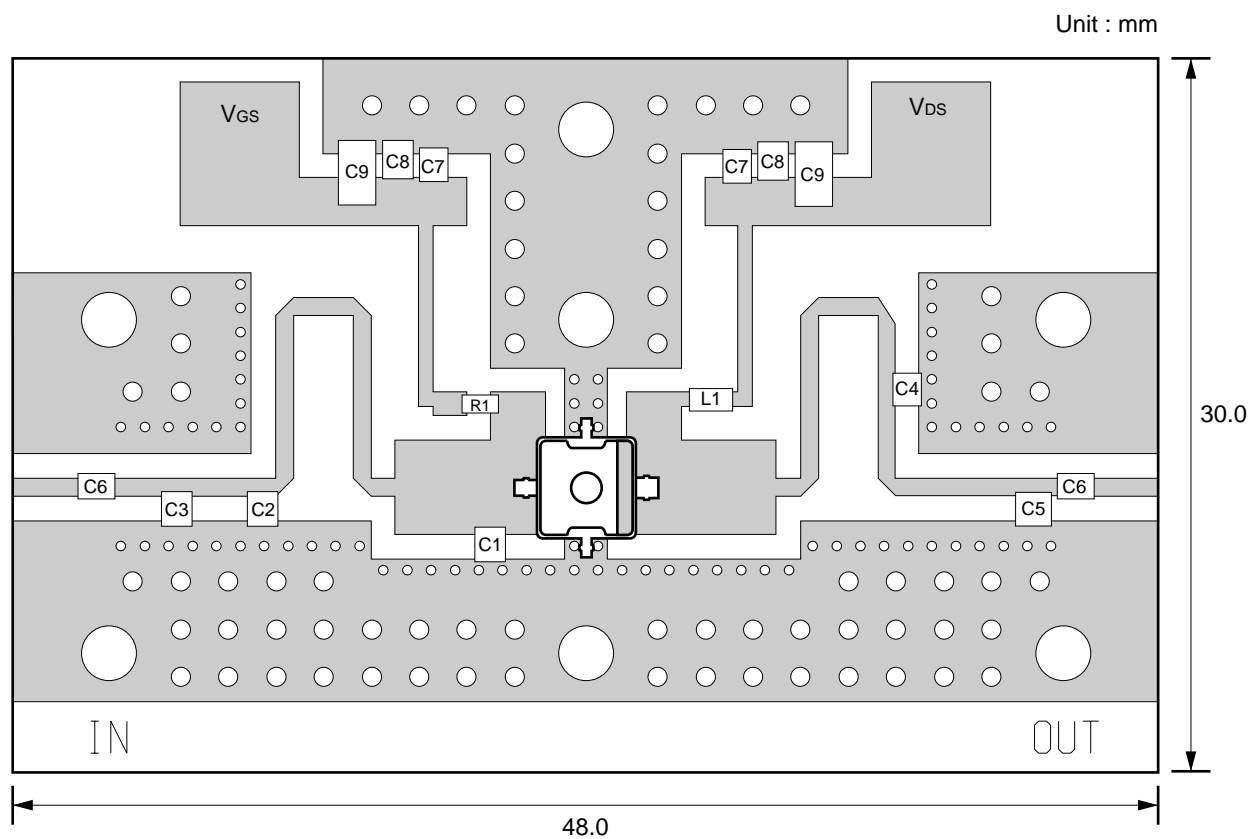
$$\Delta = S_{11} \cdot S_{22} - S_{21} \cdot S_{12}$$

LARGE SIGNAL IMPEDANCE ( $V_{DS} = 3.0\text{ V}$ ,  $I_{DS} = 300\text{ mA}$ ,  $f = 460\text{ MHz}$ )

f (MHz)	$Z_{in} (\Omega)$	$Z_{OL} (\Omega)$ <sup>Note</sup>
460	7.47 +j18.24	4.82 +j5.04

**Note**  $Z_{OL}$  is the conjugate of optimum load impedance at given voltage, idling current, input power and frequency.

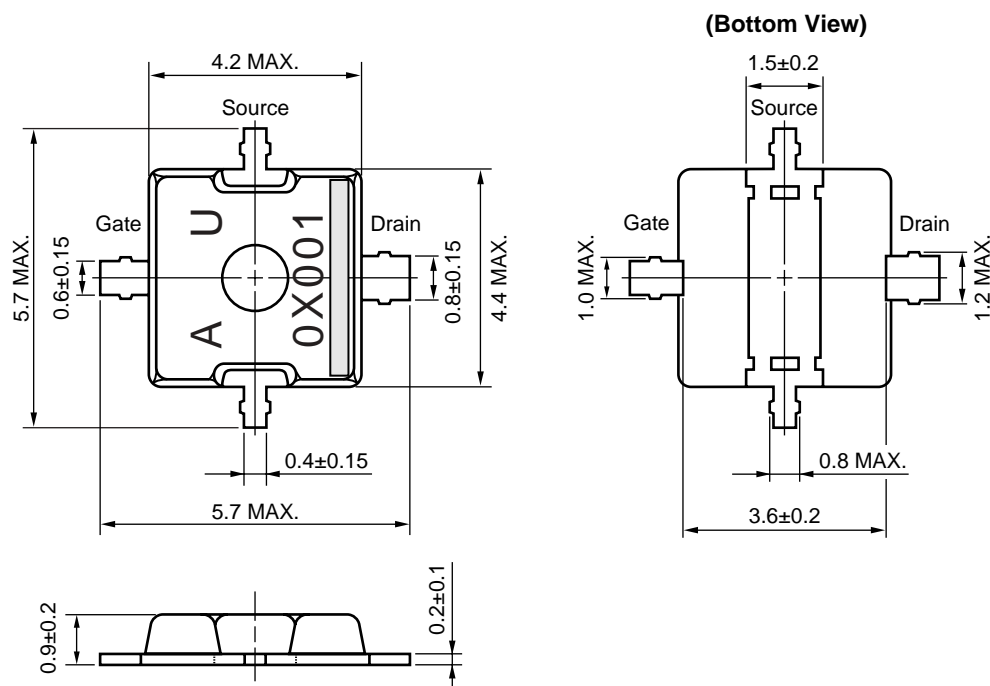
EVALUATION BOARD for 460 MHz



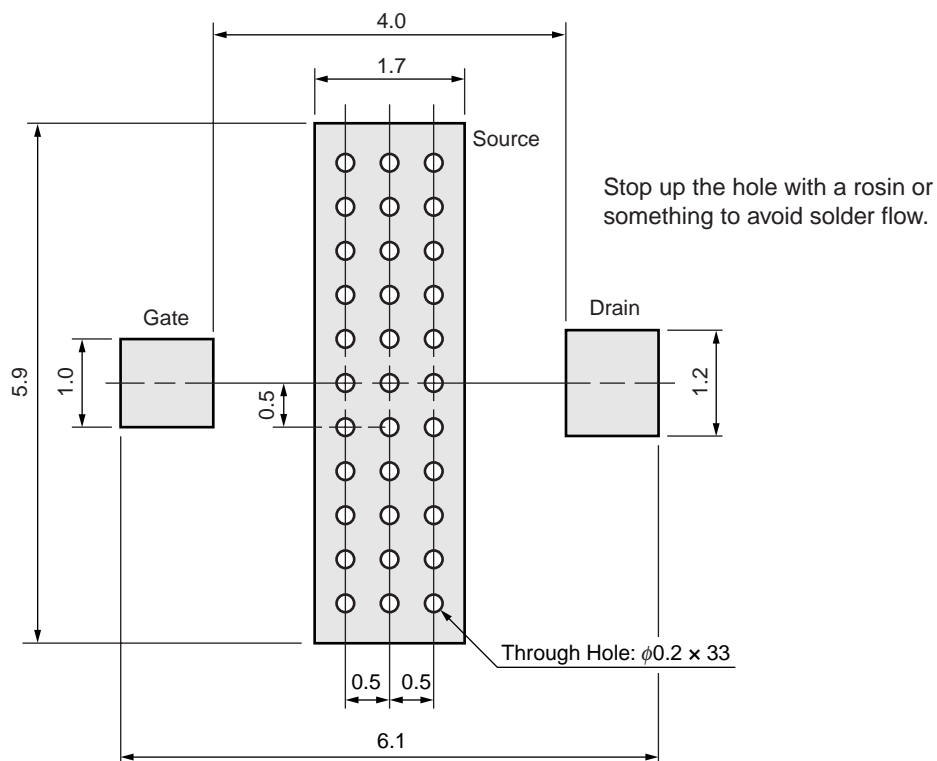
Symbol	Value	Comment
C1	9.1 pF	
C2	12 pF	
C3	20 pF	
C4	3.3 pF	
C5	13 pF	
C6	22 pF	
C7	1 000 pF	
C8	0.33 $\mu$ F	
C9	3.3 $\mu$ F - 16V	
R1	1 000 $\Omega$	
L1	22 nH	
Circuit Board	t = 0.4 mm, $\epsilon$ r = 4.5	R4775

# PACKAGE DIMENSIONS

79A (UNIT: mm)



## 79A PACKAGE RECOMMENDED P.C.B. LAYOUT (UNIT: mm)



**RECOMMENDED SOLDERING CONDITIONS**

This product should be soldered and mounted under the following recommended conditions. For soldering methods and conditions other than those recommended below, contact your nearby sales office.

Soldering Method	Soldering Conditions	Condition Symbol
Infrared Reflow	Peak temperature (package surface temperature) : 260°C or below Time at peak temperature : 10 seconds or less Time at temperature of 220°C or higher : 60 seconds or less Preheating time at 120 to 180°C : 120±30 seconds Maximum number of reflow processes : 3 times Maximum chlorine content of rosin flux (% mass) : 0.2%(Wt.) or below	IR260
VPS	Peak temperature (package surface temperature) : 215°C or below Time at temperature of 200°C or higher : 25 to 40 seconds Preheating time at 120 to 150°C : 30 to 60 seconds Maximum number of reflow processes : 3 times Maximum chlorine content of rosin flux (% mass) : 0.2%(Wt.) or below	VP215
Wave Soldering	Peak temperature (molten solder temperature) : 260°C or below Time at peak temperature : 10 seconds or less Preheating temperature (package surface temperature) : 120°C or below Maximum number of flow processes : 1 time Maximum chlorine content of rosin flux (% mass) : 0.2%(Wt.) or below	WS260
Partial Heating	Peak temperature (pin temperature) : 350°C or below Soldering time (per pin of device) : 3 seconds or less Maximum chlorine content of rosin flux (% mass) : 0.2%(Wt.) or below	HS350-P3

**Caution** Do not use different soldering methods together (except for partial heating).

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